

N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^d	Q _g (Typ.)			
40	0.012 at V _{GS} = 10 V	12	15 nC			
	0.012 at V _{GS} = 4.5 V	9	10110			

8 D

5

7 D

6 D

D

SO-8

Top View

S 1

S 2

S 3

G

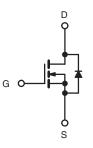
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FEATURES

- Halogen-free According to IEC 61249-2-21
 Definition
- TrenchFET[®] Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested
- Compliant to RoHS directive 2002/95/EC

APPLICATIONS

- Synchronous Rectification
- POL, IBC
 - Secondary Side



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS $T_A = 25 \degree C$, unless otherwise noted						
Parameter	Symbol	Limit	Unit			
Drain-Source Voltage		V _{DS}	40	V		
Gate-Source Voltage		V _{GS}	± 20	v		
	T _C = 25 °C		12			
Continuous Drain Current (T $= 150 ^{\circ}\text{C}$)	T _C = 70 °C	1	8			
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	^I D	12.4 ^{a, b}	Α		
	T _A = 70 °C		8.8 ^{a, b}	A		
Pulsed Drain Current		I _{DM}	50			
Avalanche Current	L = 0.1 mH	I _{AS}	15			
Avalanche Energy	L = 0.1 mm	E _{AS}	11	mJ		
Continuous Source-Drain Diode Current	T _C = 25 °C	- I _S	5	Α		
Continuous Source-Drain Diode Current	T _A = 25 °C		2.1 ^{a, b}	A		
Maximum Power Dissipation	T _C = 25 °C	– P _D	6			
	T _C = 70 °C		3.8	w		
	T _A = 25 °C		2.5 ^{a, b}	vv		
	T _A = 70 °C	1	1.6 ^{a, b}			
Operating Junction and Storage Temperature	T _J , T _{stg}	- 55 to 150	°C			

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	37	50	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	17	21	0/11		

Notes:

a. Surface Mounted on 1" x 1" FR4 board.

b. t = 10 s.

c. Maximum under Steady State conditions is 85 °C/W.

d. Based on T_C = 25 °C.

SPECIFICATIONS $T_J = 25 \ ^{\circ}C$,	uniess other	wise noted		•	•		
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	•			-	-		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	40			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		40		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	10 - 200 μ.τ		- 6			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1		3	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	lace	$V_{DS} = 40 V, V_{GS} = 0 V$			1	μA	
Zero Gale Vollage Drain Current	I _{DSS}	V_{DS} = 40 V, V_{GS} = 0 V, T_{J} = 55 °C			5		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5$ V, $V_{GS} = 10$ V	50			Α	
Drain-Source On-State Resistance ^a	B	V _{GS} = 10 V, I _D = 12.4 A		0.010			
Dialit-Source On-State Resistance	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 10.8 A		0.012		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 12.4 A		56		S	
Dynamic ^b		·			•		
Input Capacitance	C _{iss}			2000		pF	
Output Capacitance	C _{oss}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$		260			
Reverse Transfer Capacitance	C _{rss}			150			
Takal Oaka Okaana	0	$V_{DS} = 10 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 12.4 \text{ A}$		33	50	nC	
Total Gate Charge	Qg			15	23		
Gate-Source Charge	Q _{gs}	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 12.4 \text{ A}$		6.7			
Gate-Drain Charge	Q _{gd}			5.1			
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			25	40	-	
Rise Time	t _r	V_{DD} = 20 V, R_L = 2 Ω		12	20		
Turn-Off Delay Time	t _{d(off)}	$\rm I_D \cong 10$ A, $\rm V_{GEN}$ = 4.5 V, $\rm R_g$ = 1 Ω		25	40		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			10	15	ns	
Rise Time	t _r	$V_{DD} = 20 \text{ V}, \text{ R}_{L} = 2 \Omega$		15	25	-	
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D}\cong$ 10 A, V_GEN = 10 V, R_g = 1 Ω		30	45		
Fall Time	t _f			10	15		
Drain-Source Body Diode Characteristi	cs					1	
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			30	۸	
Pulse Diode Forward Current	I _{SM}				50	A	
Body Diode Voltage	V _{SD}	I _S = 10 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			30	60	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	$\frac{1}{1}$		26	52	nC	
Reverse Recovery Fall Time	ta	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^\circ\text{C}$		17.5			
Reverse Recovery Rise Time	t _b			12.5		ns	

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %

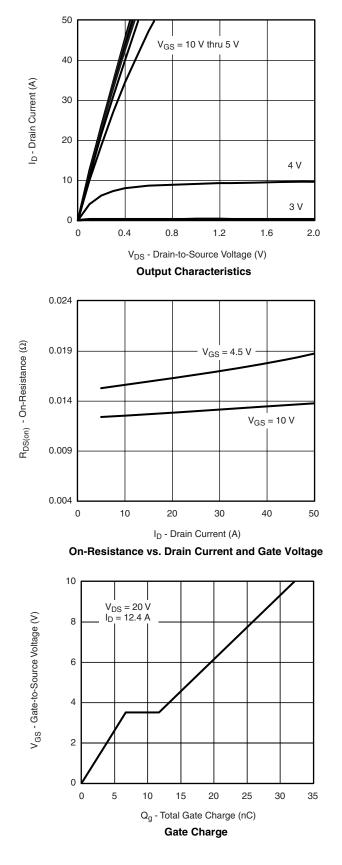
b. Guaranteed by design, not subject to production testing.

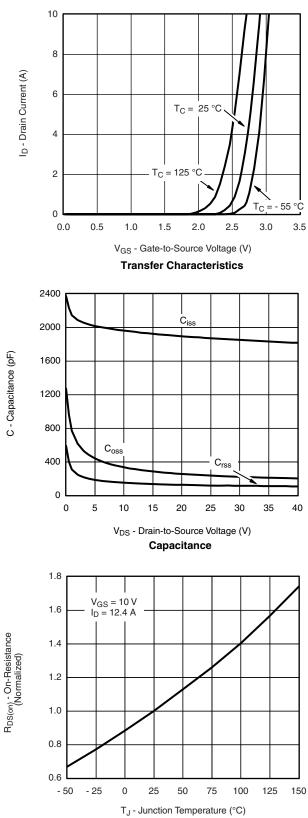
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

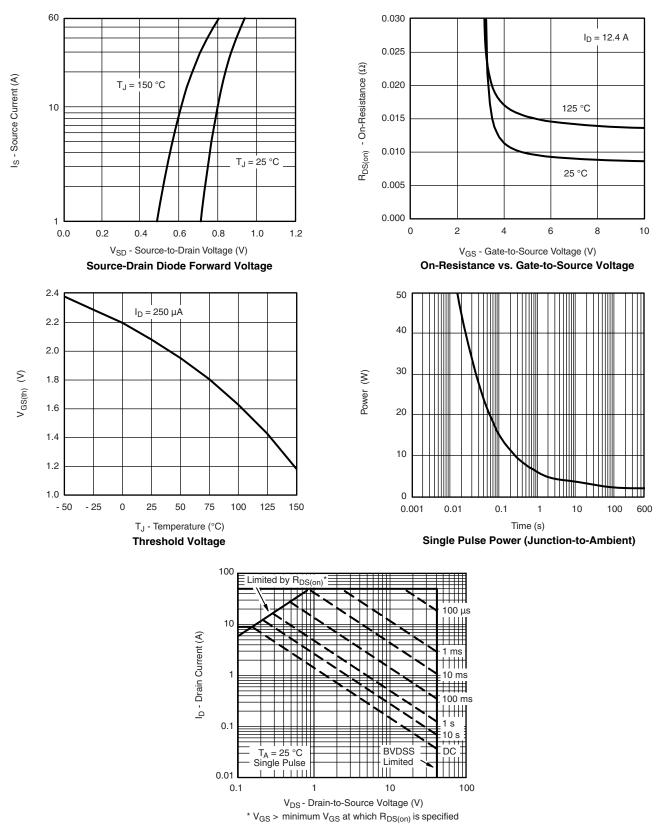




On-Resistance vs. Junction Temperature



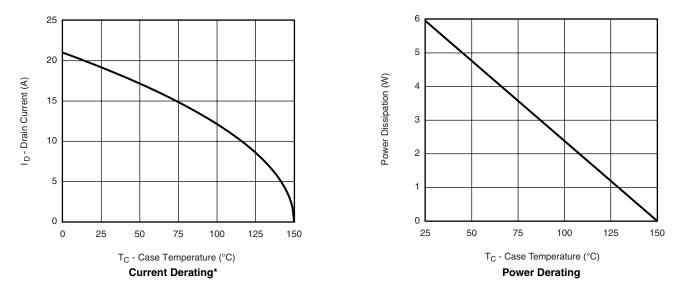
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Safe Operating Area, Junction-to-Ambient

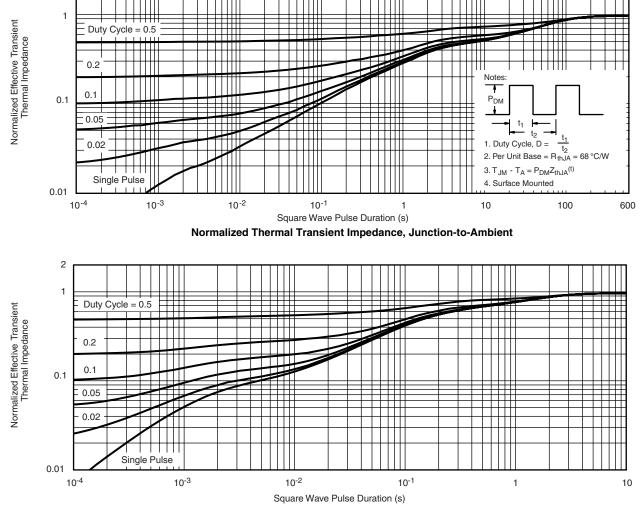


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





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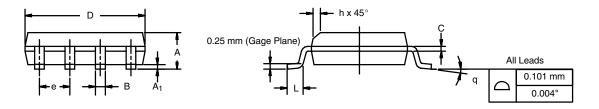
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SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012

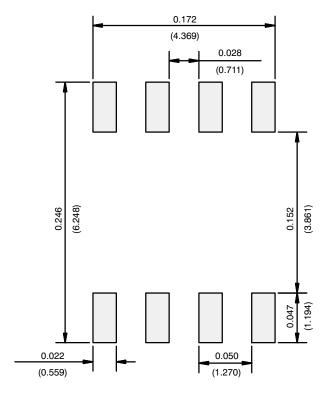




	MILLIM	IETERS	INC	HES	
DIM	Min	Max	Min	Max	
A	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8 °	0°	8°	
S	0.44	0.64	0.018	0.026	
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498					



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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